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Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild <a href="general-regarding-numbers-n

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Dec 2012

FDD10AN06A0 F085

N-Channel PowerTrench® MOSFET 60V, 50A, 10.5m Ω

Features

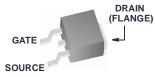
- $r_{DS(ON)} = 9.4 \text{m}\Omega \text{ (Typ.)}, V_{GS} = 10 \text{V}, I_D = 50 \text{A}$
- $Q_{q}(tot) = 28nC (Typ.), V_{GS} = 10V$
- Low Miller Charge
- Low Qrr Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant

Formerly developmental type 82560



Applications

- · Motor / Body Load Control
- · ABS Systems
- Powertrain Management
- Injection Systems
- DC-DC converters and Off-line UPS
- Distributed Power Architectures and VRMs
- Primary Switch for 12V and 24V systems







MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V _{DSS}	Drain to Source Voltage	60	V
V _{GS}	Gate to Source Voltage	±20	V
	Drain Current		
I_D	Continuous (T _C < 115°C, V _{GS} = 10V)	50	А
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 52^{\circ}C/W$)	11	А
	Pulsed	Figure 4	А
E _{AS}	Single Pulse Avalanche Energy (Note 1)	429	mJ
	Power dissipation	135	W
P_{D}	Derate above 25°C	0.9	W/°C
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-252	1.11	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252	100	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252, 1in ² copper pad area	52	°C/W

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/

Reliability data can be found at: http://www.fairchildsemi.com/products/discrete/reliability/index.html.

All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

Package	Marking	and	Orderina	Information
			0.0.0	

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD10AN06A0	FDD10AN06A0_F085	TO-252AA	330mm	16mm	2500 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Chara	acteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_C$	_{SS} = 0V	60	-	-	V
1	Zoro Cata Voltago Prain Current	$V_{DS} = 50V$		-	-	1	
IDSS	Zero Gate Voltage Drain Current	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	•	-	-	±100	nA

On Characteristics

V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\mu A$	2	-	4	V
		$I_{D} = 50A, V_{GS} = 10V$	-	0.0094	0.0105	
r _{DS(ON)}	Drain to Source On Resistance	$I_D = 50A, V_{GS} = 10V,$ $T_J = 175^{\circ}C$	-	0.020	0.023	Ω

Dynamic Characteristics

C _{ISS}	Input Capacitance	V 25V V 2V		-	1840	-	pF
Coss	Output Capacitance	V _{DS} = 25V, V _{GS} = f = 1MHz	$V_{DS} = 25V, V_{GS} = 0V,$		340	-	pF
C _{RSS}	Reverse Transfer Capacitance	1 = 11V1 Z		-	110	-	pF
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0V \text{ to } 10V$			28	37	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 2V$	$V_{DD} = 30V$	-	3.5	4.6	nC
	Gate to Source Gate Charge		I _D = 50A	-	9.8	-	nC
Q _{gs} Q _{gs2}	Gate Charge Threshold to Plateau		$I_g = 1.0 \text{mA}$	-	6.4	-	nC
Q_{gd}	Gate to Drain "Miller" Charge			-	7.8	-	nC

Switching Characteristics $(V_{GS} = 10V)$

t _{ON}	Turn-On Time		-	-	131	ns
t _{d(ON)}	Turn-On Delay Time		-	8	-	ns
t _r	Rise Time	$V_{DD} = 30V, I_{D} = 50A$	-	79	-	ns
t _{d(OFF)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 10\Omega$	-	32	-	ns
t _f	Fall Time		-	32	-	ns
t _{OFF}	Turn-Off Time		-	-	97	ns

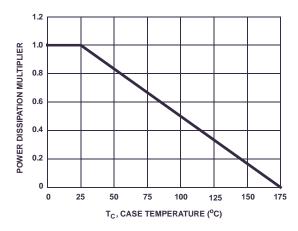
Drain-Source Diode Characteristics

V _{SD}	Source to Drain Diode Voltage	I _{SD} = 50A	-	-	1.25	V
	Source to Drain Diode voltage	I _{SD} = 25A	-	1.0	V	
t _{rr}	Reverse Recovery Time	$I_{SD} = 50A$, $dI_{SD}/dt = 100A/\mu s$	-	-	27	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 50A$, $dI_{SD}/dt = 100A/\mu s$	-	-	23	nC

Notes: 1: Starting $T_J = 25^{\circ}C$, L = 8.58mH, $I_{AS} = 10A$.

FDD10AN06A0_F085 Rev. C1





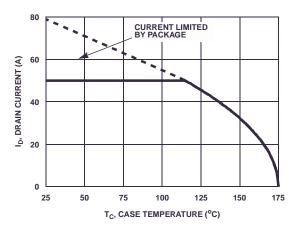


Figure 1. Normalized Power Dissipation vs Ambient Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

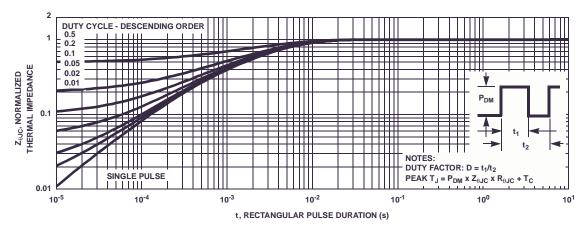


Figure 3. Normalized Maximum Transient Thermal Impedance

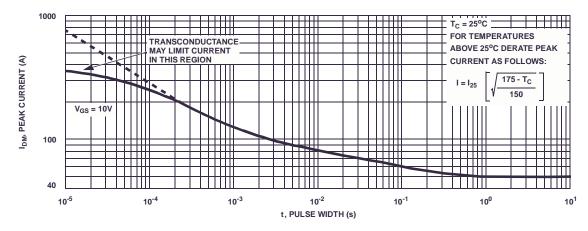
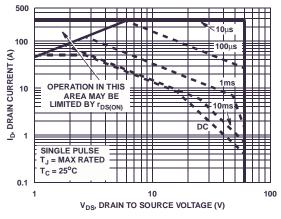


Figure 4. Peak Current Capability

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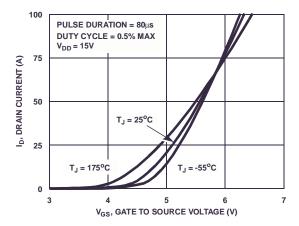
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Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability



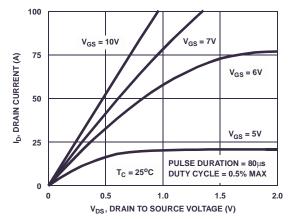
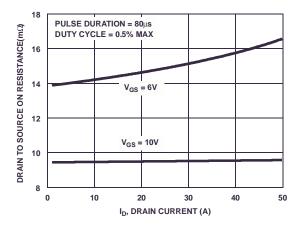


Figure 7. Transfer Characteristics

Figure 8. Saturation Characteristics



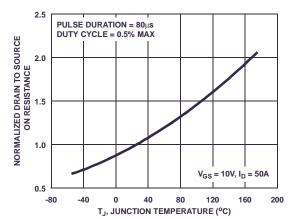


Figure 9. Drain to Source On Resistance vs Drain Current

Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

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Typical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

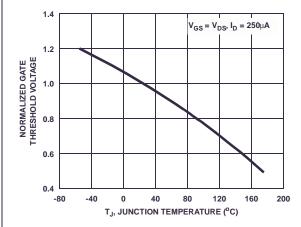


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

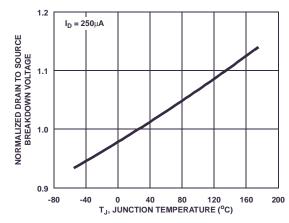


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

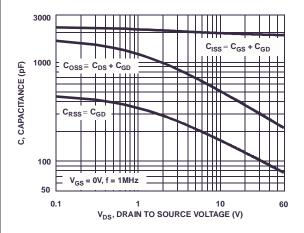


Figure 13. Capacitance vs Drain to Source Voltage

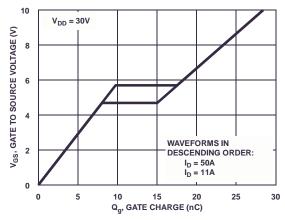


Figure 14. Gate Charge Waveforms for Constant Gate Currents

Test Circuits and Waveforms

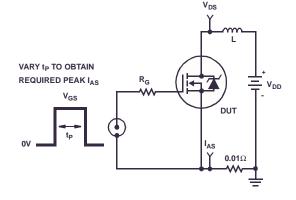


Figure 15. Unclamped Energy Test Circuit

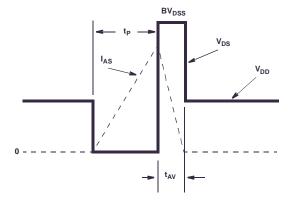


Figure 16. Unclamped Energy Waveforms

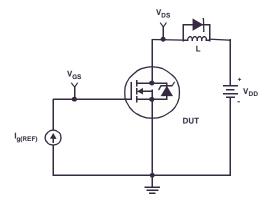


Figure 17. Gate Charge Test Circuit

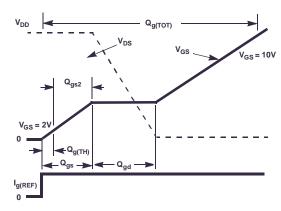


Figure 18. Gate Charge Waveforms

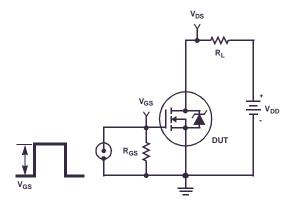


Figure 19. Switching Time Test Circuit

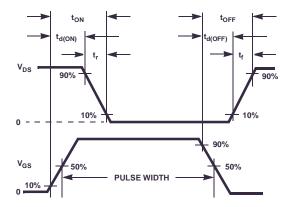


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\Theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

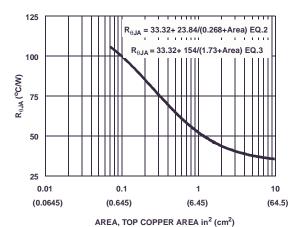
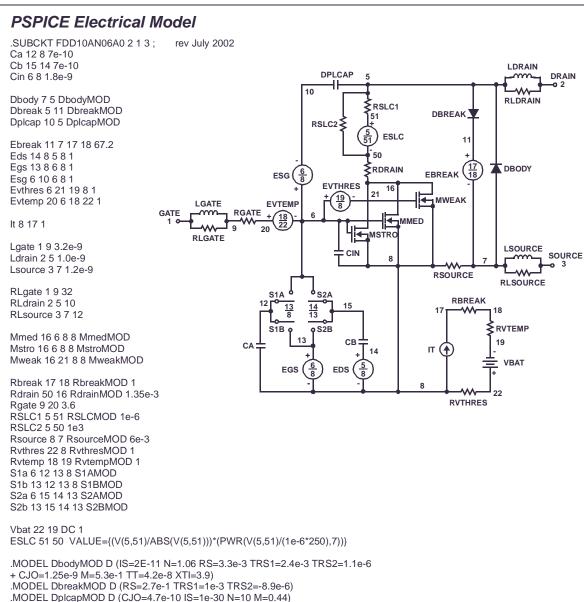


Figure 21. Thermal Resistance vs Mounting
Pad Area



.MODEL DplcapMOD D (CJO=4.7e-10 IS=1e-30 N=10 M=0.44)

.MODEL MmedMOD NMOS (VTO=3.5 KP=5.5 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=3.6)

.MODEL MstroMOD NMOS (VTO=4.25 KP=80 IS=1e-30 N=10 TOX=1 L=1u W=1u)

.MODEL MweakMOD NMOS (VTO=2.92 KP=0.03 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=36 RS=0.1)

.MODEL RbreakMOD RES (TC1=9e-4 TC2=5e-7)

.MODEL RdrainMOD RES (TC1=2.5e-2 TC2=7.8e-5)

.MODEL RSLCMOD RES (TC1=1e-3 TC2=3.5e-5)

.MODEL RsourceMOD RES (TC1=1e-3 TC2=1e-6)

.MODEL RvthresMOD RES (TC1=-5.3e-3 TC2=-1.3e-5)

.MODEL RvtempMOD RES (TC1=-2.6e-3 TC2=1.3e-6)

.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-8 VOFF=-5)

.MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-5 VOFF=-8)

.MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2 VOFF=-1.5) .MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-1.5 VOFF=-2)

.ENDS

Note: For further discussion of the PSPICE model, consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

SABER Electrical Model REV July 2002 template FDD10AN06A0 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=2e-11,nl=1.06,rs=3.3e-3,trs1=2.4e-3,trs2=1.1e-6,cjo=1.25e-9,m=5.3e-1,tt=4.2e-8,xti=3.9) dp..model dbreakmod = (rs=2.7e-1.trs1=1e-3.trs2=-8.9e-6) dp..model dplcapmod = (cjo=4.7e-10,isl=10e-30,nl=10,m=0.44) $m..model mmedmod = (type=_n, vto=3.5, kp=5.5, is=1e-30, tox=1)$ m..model mstrongmod = (type=_n,vto=4.25,kp=80,is=1e-30, tox=1) m..model mweakmod = $(type=_n, vto=2.92, kp=0.03, is=1e-30, tox=1, rs=0.1)$ I DRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-8,voff=-5) DPLCAP DRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-5,voff=-8) 10 sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-2,voff=-1.5) RLDRAIN sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-1.5,voff=-2) ≹RSLC1 c.ca n12 n8 = 7e-10c.cb n15 n14 = 7e-10RSLC2 ≥ ISCL c.cin n6 n8 = 1.8e-9DBREAK 3 dp.dbody n7 n5 = model=dbodymod **≨**RDRAIN dp.dbreak n5 n11 = model=dbreakmod 6 8 ESG (DBODY dp.dplcap n10 n5 = model=dplcapmod **EVTHRES** 21 MWFAK **LGATE EVTEMP** spe.ebreak n11 n7 n17 n18 = 67.2 _{GATE} **RGATE** 1822 spe.eds n14 n8 n5 n8 = 1 FRREAK MMED ₩-20 spe.egs n13 n8 n6 n8 = 1 ■MSTRC RLGATE spe.esg n6 n10 n6 n8 = 1 CIN spe.evthres n6 n21 n19 n8 = 1 SOURCE 8 spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1RBREAK <u>14</u> 13 I.lgate n1 n9 = 3.2e-9 18 1.1drain n2 n5 = 1.0e-9o S2B **₹**RVTEMP S₁B I.Isource n3 n7 = 1.2e-9СВ 19 IT 14 res.rlgate n1 n9 = 32 VRAT <u>5</u> 8 res.rldrain n2 n5 = 10 **FGS** FDS res.rlsource n3 n7 = 12 **RVTHRES** m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u res.rbreak n17 n18 = 1, tc1=9e-4,tc2=5e-7 res.rdrain n50 n16 = 1.35e-3, tc1=2.5e-2,tc2=7.8e-5 res.rgate n9 n20 = 3.6 res.rslc1 n5 n51 = 1e-6, tc1=1e-3,tc2=3.5e-5 res.rslc2 n5 n50 = 1e3res.rsource n8 n7 = 6e-3, tc1=1e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-5.3e-3,tc2=-1.3e-5 res.rvtemp n18 n19 = 1, tc1=-2.6e-3,tc2=1.3e-6 sw vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl (v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/250))**7))

SPICE Thermal Model

REV 23 July 2002 FDD10AN06A0T

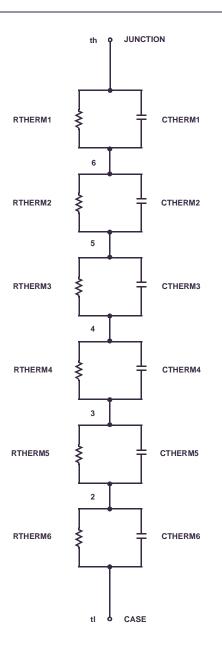
CTHERM1 TH 6 3.2e-3 CTHERM2 6 5 3.3e-3 CTHERM3 5 4 3.4e-3 CTHERM4 4 3 3.5e-3 CTHERM5 3 2 6.4e-3 CTHERM6 2 TL 1.9e-2

RTHERM1 TH 6 5.5e-4 RTHERM2 6 5 5.0e-3 RTHERM3 5 4 4.5e-2 RTHERM4 4 3 1.5e-1 RTHERM5 3 2 3.37e-1 RTHERM6 2 TL 3.5e-1

SABER Thermal Model

SABER thermal model FDD10AN06A0T template thermal_model th tl thermal_c th, tl { ctherm.ctherm1 th 6=3.2e-3 ctherm.ctherm2 6.5=3.3e-3 ctherm.ctherm3 5.4=3.4e-3 ctherm.ctherm4 4.3=3.5e-3 ctherm.ctherm5 3.2=6.4e-3 ctherm.ctherm6 2.1=1.9e-2 rtherm.rtherm1 th 6=5.5e-4 rtherm.rtherm2 6.5=5.0e-3 rtherm.rtherm3 5.4=4.5e-2 rtherm.rtherm4 5.2e-2 rtherm.rtherm5 5.2e-1 rtherm.rtherm5

rtherm.rtherm6 2 tl =3.5e-1







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- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

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Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

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Datasheet Identification	Product Status	Definition
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Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
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